Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/719,385	O'TOOLE ET AL.
Examiner	Art Unit
Yunsoo Kim	1644

SEARCHED					
Class	Subclass	Date	Examiner		
530	350	1/27/2005	YK		
514	2	1/27/2005	YK		
536	23.1	11/1/2005	YK		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
530	350	1/27/2005	YK	
514	2	1/27/2005	YK	
536	23.1	11/1/2005	YK	
SEQ ID NO:2 interference, updated		10/21/2005	YK	

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
seq ID No:2,20,26 search from STIC	1/3/2005	YK
domestic priority 60/428,094 11/21/02	1/3/2005	YK
inventor search from PALM	1/3/2005	UL
SEQ ID NO:2 search encompasses the SEQ ID NO:3-19 as they are closely related. 1 aa differs of 1753 aa	11/1/2005	YK
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